

Title (en)

METHOD FOR EXAMINING A GAS BY MASS SPECTROMETRY AND MASS SPECTROMETER

Title (de)

VERFAHREN ZUR MASSENSPEKTROMETRISCHEN UNTERSUCHUNG EINES GASES UND MASSENSPEKTROMETER

Title (fr)

PROCÉDÉ D'ANALYSE D'UN GAZ PAR SPECTROMÉTRIE DE MASSE ET SPECTROMÈTRE DE MASSE

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Application

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Abstract (en)

[origin: WO2016177503A1] The invention relates to a method for examining a gas (4) by mass spectrometry, comprising: ionizing the gas (4) for producing ions (4a, 4b), and storing, exciting and detecting at least some of the produced ions (4a, 4b) in an FT ion trap (2). In the method, producing and storing the ions (4a, 4b) in the FT ion trap (2) and/or exciting the ions (4a, 4b) prior to the detection of the ions (4a, 4b) in the FT ion trap (2) comprises at least one selective IFT excitation, in particular a SWIFT excitation (10), which is dependent on the mass-to-charge ratio (m/z) of the ions (4a, 4b). The invention further relates to a mass spectrometer (1).

IPC 8 full level

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